

A scalable model based RTL framework zamiaCAD for static analysis

Tšepurov, Anton; Jenihhin, Maksim; Raik, Jaan; Tihhomirov, Valentin 2012 IEEE/IFIP 20th International Conference on VLSI and System-on-Chip (VLSI-SoC) : October 7-10, 2012 Santa Cruz, USA Dream Inn, Santa Cruz, USA : [proceedings] 2012 / p. 171-176 : ill

Application of high-level decision diagrams for simulation-based verification tasks

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Applications of the open source HW design framework zamiaCAD

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Design error diagnosis using backtrace algorithm on decision diagrams

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High-level design error diagnosis using backtrace on decision diagrams

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PSL assertion checking using temporally extended high-level decision diagrams

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zamiaCAD : open source platform for advanced hardware design

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Teaching digital test with BIST analyzer

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VHDL design debug framework based on zamiaCAD

Tihhomirov, Valentin; Tšepurov, Anton; Saif Abrar, Syed; Jenihhin, Maksim; Raik, Jaan DATE 2013 : Design Automation and Test in Europe, March 18-22, 2013, Grenoble, France 2013 / [1] p. : ill